

40mΩ, 1200V Silicon Carbide Power MOSFET

GENERAL DESCRIPTION

- ◆ 3rd generation SiC MOSFET technology
- ◆ High blocking voltage with low on-resistance
- ◆ High-speed switching with low capacitance
- ◆ Fast intrinsic diode with low reverse recovery

BENEFIT

- ◆ Reduce switching losses and minimize gate ringing
- ◆ Higher system efficiency
- ◆ High Temperature Application
- ◆ Hard Switching Higher Reliability

APPLICATIONS

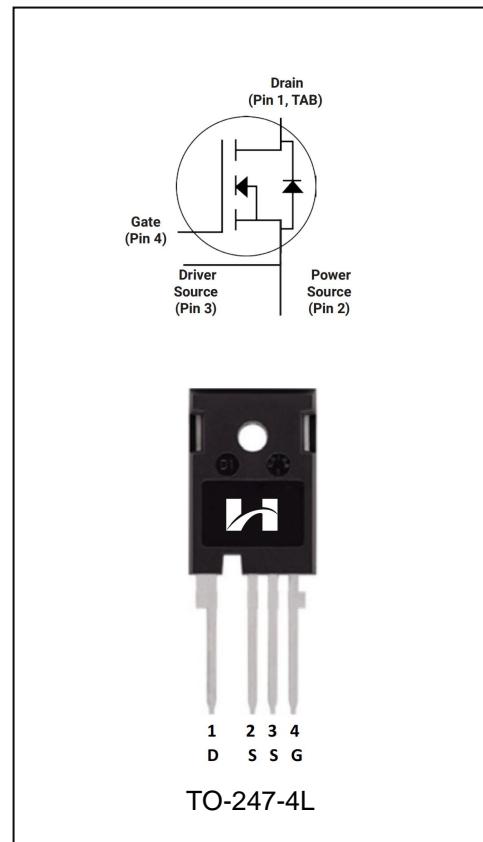
- ◆ High voltage DC / DC converters
- ◆ Switched mode power supplies
- ◆ Motor Drives

Features

◆ $V_{DS}=1200V$, $I_D=55A$

◆ $R_{DS(on)}$

TYP: 40mΩ@ $V_{GS}= 20V$



ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SC3K040120	TO-247-4L	SC3K040120	Pb free	Tube

ABSOLUTE MAXIMUM RATINGS ($T_C=25^\circ\text{C}$ unless otherwise noted)

Characteristics	Symbol	Test conditions		Value	Unit
Drain-Source Voltage	$V_{DS\max}$	$V_{GS}=0\text{V}$, $I_D=100\mu\text{A}$		1200	V
Gate-Source Voltage (dynamic)	$V_{GS\max}$	AC($f>1\text{Hz}$)		-10/+25	
Gate-Source Voltage (static)	V_{GSop}	Static		-5/+20	
Continuous Drain Current:	I_D	$V_{GS}=20\text{V}$	$T_C=25^\circ\text{C}$	55	A
			$T_C=100^\circ\text{C}$	39	
Pulsed Drain Current:	$I_{D(\text{pulse})}$	$T_C=25^\circ\text{C}$		117	
Short Circuit Capability	t_{sc}	$V_{DD}=800\text{V}$, $V_{GS}=20\text{V}$		3	μs
Short Circuit Capability	I_{BS}	$V_{DD}=800\text{V}$, $V_{GS}=20\text{V}$		600	A
Total power dissipation	P_D	$T_C=25^\circ\text{C}$		300	W
Operating Junction Temperature	T_j	--		-55 to 175	$^\circ\text{C}$
Storage Temperature	T_{stg}	--		-55 to 150	

THERMAL CHARACTERISTICS

Characteristics	Symbol	MAX			Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.5			$^\circ\text{C/W}$

ELECTRICAL CHARACTERISTICS

Characteristics	Symbol	Test conditions		Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0\text{V}$, $I_D=100\mu\text{A}$		1200	--	--	V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS}=V_{GS}$ $I_D=10\text{mA}$	$T_j=25^\circ\text{C}$	1.8	3.5	3.9	
			$T_j=150^\circ\text{C}$	--	2.6	--	
			$T_j=175^\circ\text{C}$	--	2.5	--	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=1200\text{V}$, $V_{GS}=0\text{V}$		--	--	100	μA
Gate-Source Leakage Current	I_{GS}	$V_{GS}=20\text{V}$, $V_{DS}=0\text{V}$		--	--	200	nA
Gate-Source Leakage Current	I_{GS}	$V_{GS}=-5\text{V}$, $V_{DS}=0\text{V}$		--	--	-200	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS}=20\text{V}$ $I_D=40\text{A}$	$T_j=25^\circ\text{C}$	--	40	44	$\text{m}\Omega$
			$T_j=150^\circ\text{C}$	--	61	--	
			$T_j=175^\circ\text{C}$	--	69	--	
Transconductance	g_{fs}	$V_{GS}=20\text{V}$ $I_D=40\text{A}$	$T_j=25^\circ\text{C}$	--	22	--	S
			$T_j=150^\circ\text{C}$	--	20	--	
			$T_j=175^\circ\text{C}$	--	19	--	
Internal gate input resistance	$R_{g(\text{int})}$	$f=1\text{MHz}$, $I_D=0\text{A}$			2		Ω
Input capacitance	C_{iss}	$V_{DS}=1000\text{V}$		--	2920	--	pF
Output capacitance	C_{oss}		$V_{GS}=0\text{V}$	--	151	--	
Reverse transfer capacitance	C_{rss}		$f=1\text{MHz}$	--	8.6	--	
Total gate charge	Q_g	$V_{DS}=800\text{V}$		--	143.6	--	nC
Gate-source charge	Q_{gs}		$V_{GS}=-5\text{V}/20\text{V}$	--	40.2	--	
Gate-drain charge	Q_{gd}		$I_D=40\text{A}$	--	74.5	--	

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Turn-On Switching Energy	E _{ON}	$V_{DS}=800V, V_{GS}=-5V/20V$ $ID=40A, R_{G(ext)}=1.5\Omega$ $L=450\mu H$	--	596	--	uJ
Turn-Off Switching Energy	E _{OFF}		--	451	--	
Turn-On Delay Time	t _{d(on)}	$V_{DS}=800V$ $V_{GS}=-5V/20V$ $ID=40A, R_{G(ext)}=1.5\Omega$ $L=450\mu H$	--	23.1	--	nS
Rise Time	t _r		--	33.6	--	
Turn-Off Delay Time	t _{d(off)}		--	35.8	--	
Fall Time	t _f		--	19.5	--	
Avalanche Capability	E _{AS}	$V_{DD}=100V, V_{GS}=20V$ $L=2mH$	--	669	--	mJ
	I _{Av}		--	26	--	A

REVERSE DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Diode Forward Current	I _s	$V_{GS}=-5V$	--	70	--	A
Diode Forward Voltage	V _{SD}	$V_{GS}=-5V$ I _{SD} =20A	T _j =25°C	--	3.9	V
			T _j =150°C	--	3.5	
			T _j =175°C	--	3.4	
Reverse Recovery time	t _{rr}	$V_{GS}=-5V, I_{SD}=40A$ $V_R=800V$ dif/dt=4000A/μs		21.6		nS
Reverse Recovery Charge	Q _{rr}			369.4		nC
Peak Reverse Recovery Current	I _{rrm}			31		A

Typical Performance Characteristics

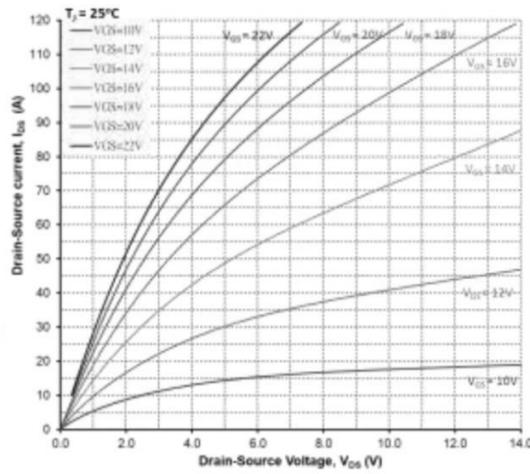
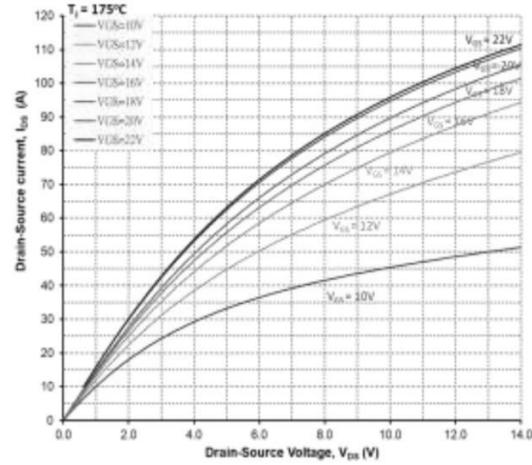
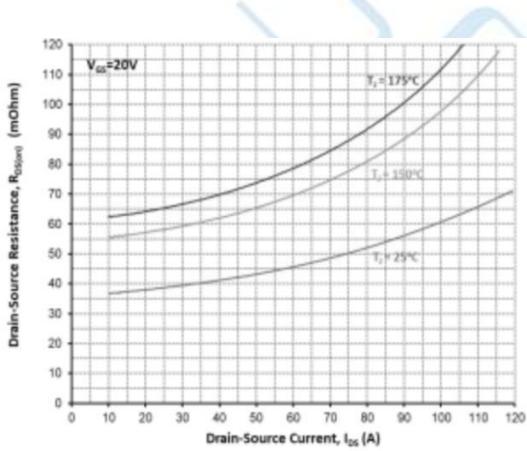
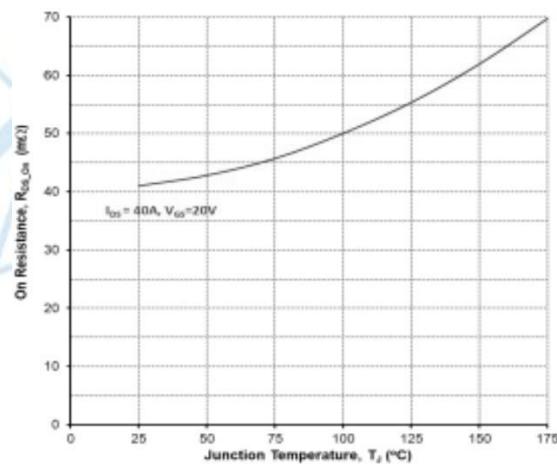
Figure 1. Output Characteristics, $T_J = 25^\circ\text{C}$ Figure 2. Output Characteristics, $T_J = 175^\circ\text{C}$ Figure 3. On-Resistance vs. Drain Current
For Various Temperatures

Figure 4. On-Resistance vs. Temperature

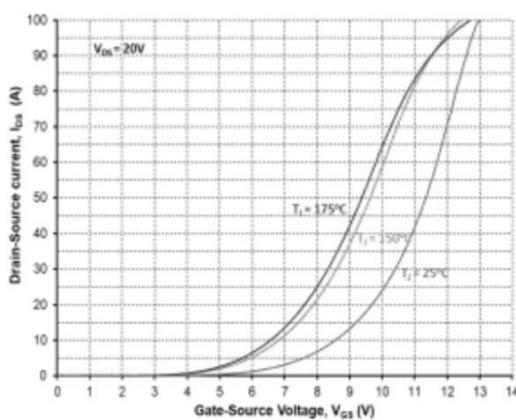


Figure 5. Transfer Characteristic For Various Junction Temperatures

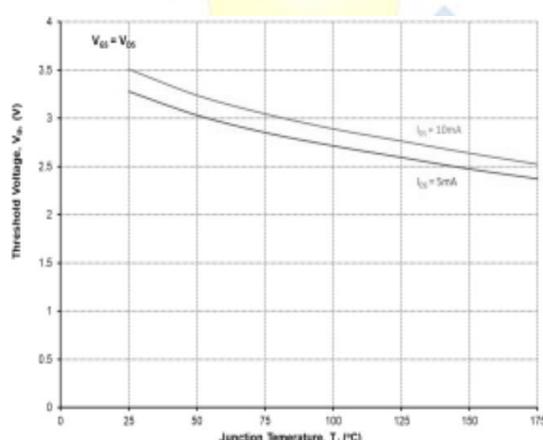


Figure 6. Threshold Voltage vs. Temperature

Typical Performance Characteristics

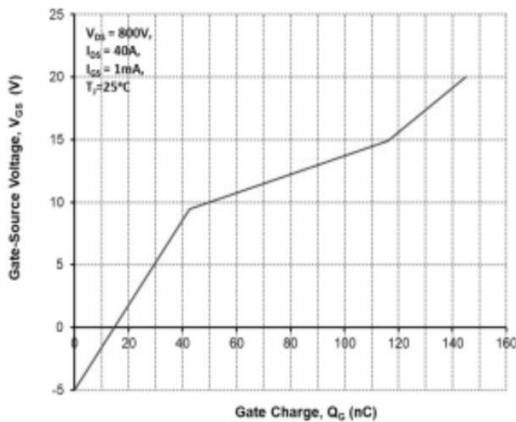


Figure 7. Gate Charge Characteristics

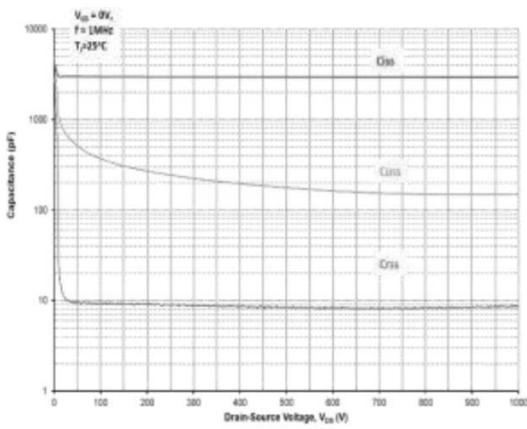


Figure 8. Capacitances vs. Drain-Source Voltage (0-1000V)

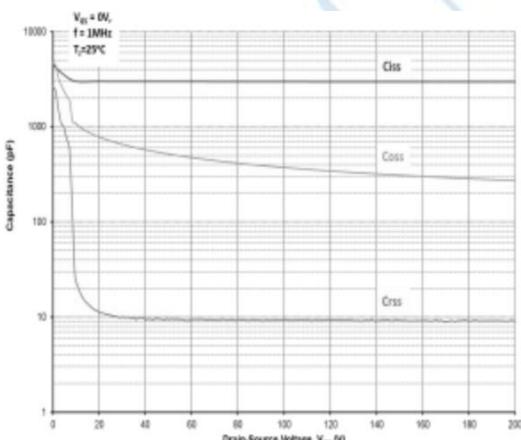


Figure 9. Capacitances vs. Drain-Source Voltage (0-200V)

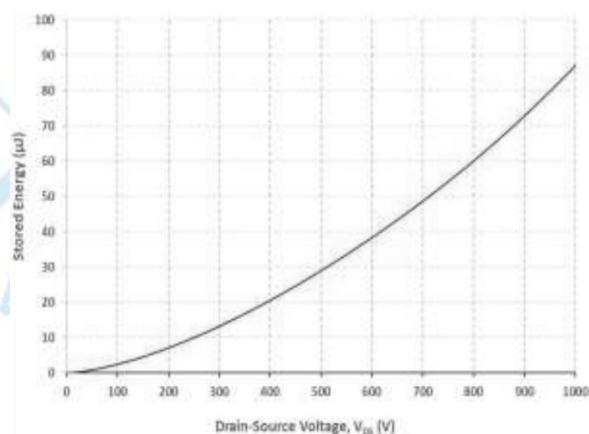


Figure 10. Output Capacitor Stored Energy

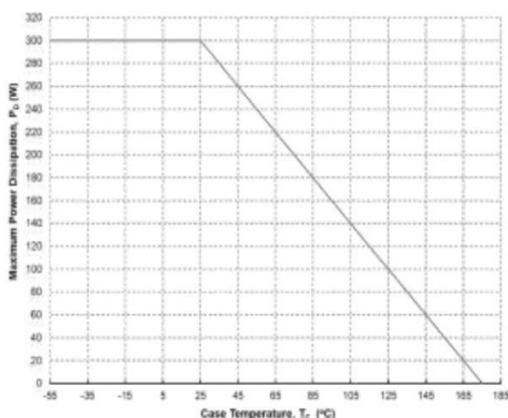


Figure 11. Maximum Power Dissipation Derating vs. Case Temperature

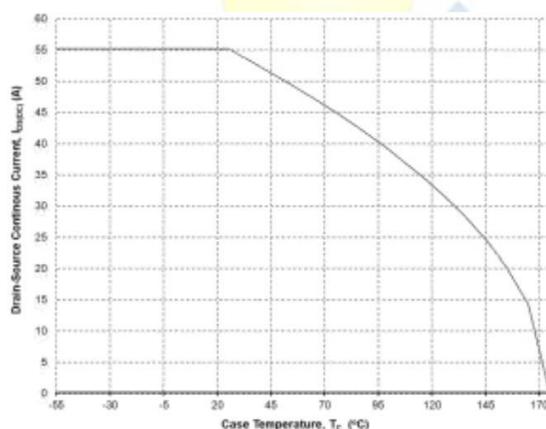


Figure 12. Continuous Drain Current Derating vs. Case Temperature

Typical Performance Characteristics

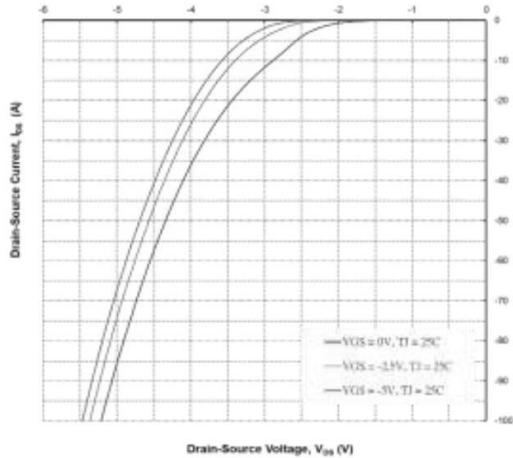


Figure 13. Body Diode Characteristics @ 25°C

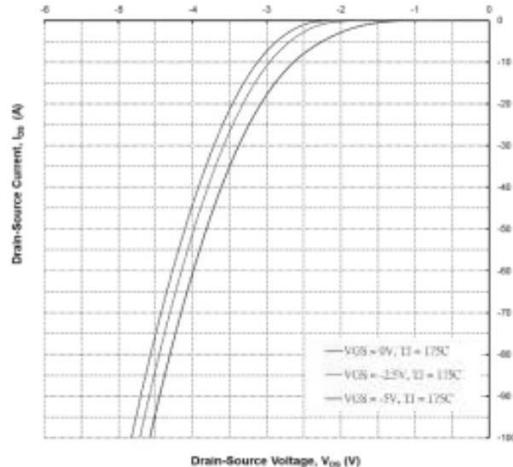


Figure 14. Body Diode Characteristics @ 175°C

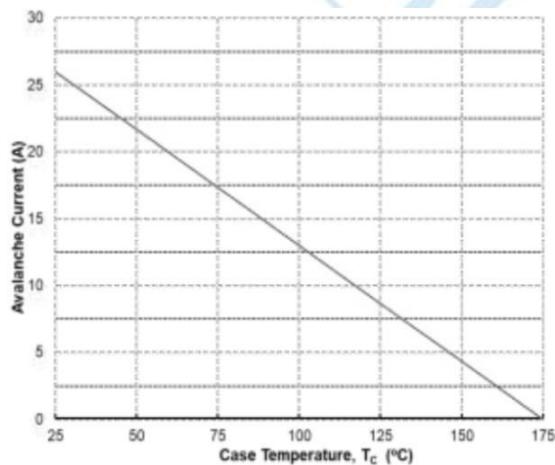


Figure 15. Single Avalanche vs. Temperature

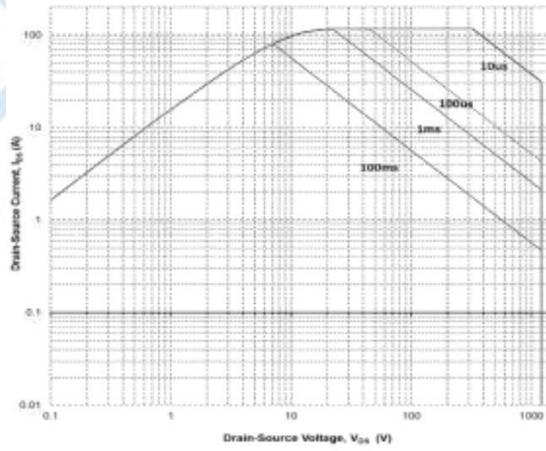
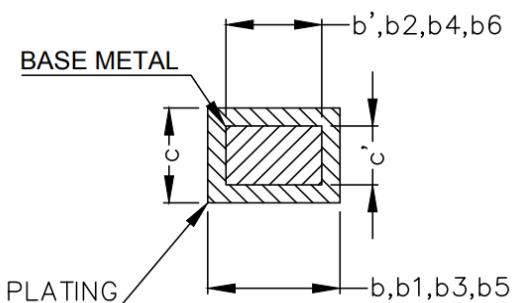
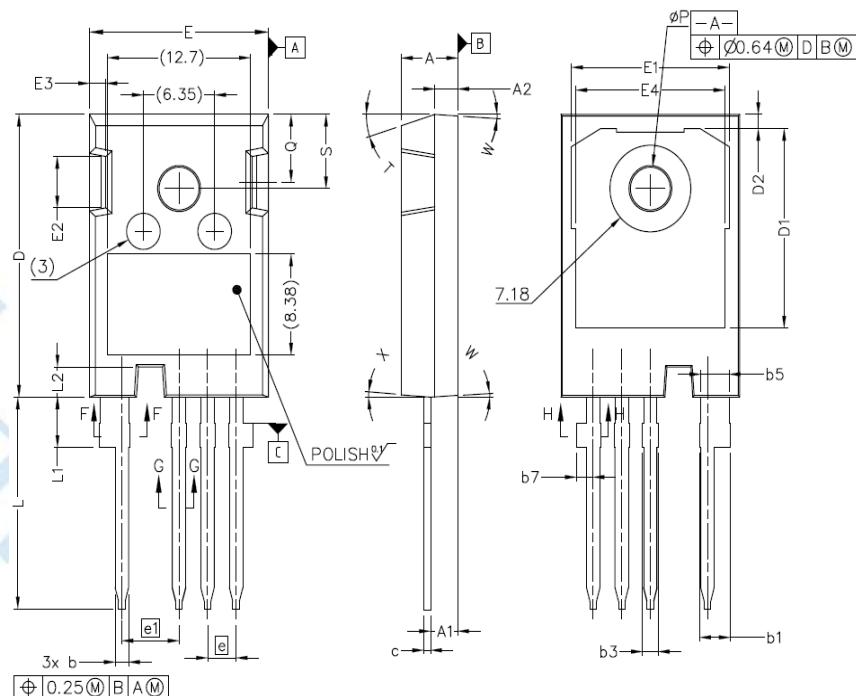


Figure 16. Safe Operating Area

Package Dimensions of TO-247-4L



SECTION "F-F", "G-G" AND "H-H"
SCALE: NONE

SYMBOL	MILLIMETERS		SYMBOL	MILLIMETERS		SYMBOL	MILLIMETERS	
	MIN	MAX		MIN	MAX		MIN	MAX
A	4.83	5.21	A1	2.29	2.54	A2	1.91	2.16
b'	1.07	1.28	b	1.07	1.33	b1	2.39	2.94
b2	2.39	2.84	b3	1.07	1.60	b4	1.07	1.50
b5	2.39	2.69	b6	2.39	2.64	B7	1.3	1.7
c'	0.55	0.65	c	0.55	0.68	D	23.30	23.60
D1	16.25	17.65	D2	0.95	1.25	E	15.75	16.13
E1	13.10	14.15	E2	3.68	5.10	E3	1.00	1.90
E4	12.38	13.43	e1	5.08BSC		N	4	
e	2.54BSC		X	4° REF		T	17.5° REF	
L1	3.97	4.37	L2	2.35	2.65	ΦP	3.51	3.65
Q	5.49	6.00	S	6.04	6.30	L	17.31	17.82
W	3.5° REF							

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